

Reliability Data Summary:			
QV DEVICE NAME:		DB-LS	
Hi-real test	Sample size(PC)	Condition	ACC/REJ
High Temperature Reverse Bias	77	Ta=150°C±5°C VR=480V. for 1000 Hrs.	ACC
Thermal Fatigue Testing	77	ON : 300 sec / Off : 300 sec for 1000 cycles	ACC
Solder resistance	77	260±5°C for 10±2 Sec.	ACC
Thermal Shock	77	55°C±5°C/5MIN AND 150±5°C/5MIN for 100 cycles	ACC
Electrical Characteristic		Floring	Maria de la Caracteria de
Summary:		Electrical characteris	nics are not impacted
List of Affected Parts:		Note: Only the standard (off the shelf) part numbers are this PCN are shown in the customer specific PCN adde Customized Portal.	endum in the PCN email notification, or on the PCN
Part Number	New spec version	Addition	Mark
DB101LS DB103LS DB104LS DB102LS DB105LS DB106LS DB107LS	DB101LS-DB107LS 202004-97-E	Including to House #	
DB151LS-DB157LS	DB151LS~DB157LS 202004-97-C	Including to House #	
DB159LS	DB159LS 202004-97-A	Including to House #	
DB201LS ~DB207LS	DB201LS - DB207LS 202004-97A	Including to House #	
DB207LS	DB201LS - DB207LS 202004-97A	Including to House #	
HDB208LS	HDB208LS 202004-97-A	Including to House #	
LDB101S LDB103S LDB104S LDB102S LDB105S LDB106S LDB107S	LDB101S ~ LDB107S 202004-97-B	Including to House #	
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